

**Search Notes**

Application/Control No.

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Examiner

Hai H. Huynh

Applicant(s)/Patent under  
Reexamination

WEISS ET AL.

Art Unit

3747

**SEARCHED**

Class	Subclass	Date	Examiner
123	295	3/27/2007	HHH
123	299	3/27/2007	HHH
123	305	3/27/2007	HHH
123	443	3/27/2007	HHH
123	325	3/27/2007	HHH
123	332	3/27/2007	HHH
123	406.23	3/27/2007	HHH
123	406.47	3/27/2007	HHH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	3/27/2007	HHH